Intel - 5SGXMB6R3F40C4N Datasheet

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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	225400
Number of Logic Elements/Cells	597000
Total RAM Bits	53248000
Number of I/O	432
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1517-FBGA (40x40)
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxmb6r3f40c4n

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 2 of 2)

Symbol	Description	Condition	Min (4)	Typ	Max (4)	Unit
t_{RAMP}	Power supply ramp time	Standard POR	200 µs	—	100 ms	—
		Fast POR	200 µs	—	4 ms	—

Notes to Table 6:

(1) V_{CCPD} must be 2.5 V when V_{CCIO} is 2.5, 1.8, 1.5, 1.35, 1.25 or 1.2 V. V_{CCPD} must be 3.0 V when V_{CCIO} is 3.0 V.

(2) If you do not use the design security feature in Stratix V devices, connect V_{CCBAT} to a 1.2- to 3.0-V power supply. Stratix V power-on-reset (POR) circuitry monitors V_{CCBAT}. Stratix V devices will not exit POR if V_{CCBAT} stays at logic low.

(3) C2L and I2L can also be run at 0.90 V for legacy boards that were designed for the C2 and I2 speed grades.

(4) The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

Table 7 lists the transceiver power supply recommended operating conditions for Stratix V GX, GS, and GT devices.

Table 7. Recommended Transceiver Power Supply Operating Conditions for Stratix V GX, GS, and GT Devices (Part 1 of 2)

Symbol	Description	Devices	Minimum (4)	Typical	Maximum (4)	Unit
V_{CCA_GXBL} (1), (3)	Transceiver channel PLL power supply (left side)	GX, GS, GT	2.85	3.0	3.15	V
			2.375	2.5	2.625	
V_{CCA_GXBR} (1), (3)	Transceiver channel PLL power supply (right side)	GX, GS	2.85	3.0	3.15	V
			2.375	2.5	2.625	
V_{CCA_GTBR}	Transceiver channel PLL power supply (right side)	GT	2.85	3.0	3.15	V
V_{CCHIP_L}	Transceiver hard IP power supply (left side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
	Transceiver hard IP power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
V_{CCHIP_R}	Transceiver hard IP power supply (right side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
	Transceiver hard IP power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
V_{CCHSSI_L}	Transceiver PCS power supply (left side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
	Transceiver PCS power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
V_{CCHSSI_R}	Transceiver PCS power supply (right side; C1, C2, I2, and I3YY speed grades)	GX, GS, GT	0.87	0.9	0.93	V
	Transceiver PCS power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades)	GX, GS, GT	0.82	0.85	0.88	V
V_{CCR_GXBL} (2)	Receiver analog power supply (left side)	GX, GS, GT	0.82	0.85	0.88	V
			0.87	0.90	0.93	
			0.97	1.0	1.03	
			1.03	1.05	1.07	

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)

Symbol	Description	Conditions	Resistance Tolerance				Unit
			C1	C2,I2	C3, I3, I3YY	C4, I4	
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±30	±30	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±35	±35	±50	±50	%
100-Ω R_D	Internal differential termination (100-Ω setting)	V_{CCPD} = 2.5 V	±25	±25	±25	±25	%

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

Equation 1. OCT Variation Without Recalibration for Stratix V Devices *(1), (2), (3), (4), (5), (6)*

$$R_{OCT} = R_{SCAL}\left(1 + \langle\frac{dR}{dT} \times \Delta T\rangle \pm \langle\frac{dR}{dV} \times \Delta V\rangle\right)$$

Notes to Equation 1:

(1) The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO}.

(2) R_{SCAL} is the OCT resistance value at power-up.

(3) ΔT is the variation of temperature with respect to the temperature at power-up.

(4) ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.

(5) dR/dT is the percentage change of R_{SCAL} with temperature.

(6) dR/dV is the percentage change of R_{SCAL} with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 1 of 2) *(1)*

Symbol	Description	V_{CCIO} (V)	Typical	Unit
dR/dV	OCT variation with voltage without recalibration	3.0	0.0297	%/mV
		2.5	0.0344	
		1.8	0.0499	
		1.5	0.0744	
		1.2	0.1241	

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 2 of 2) (1)

Symbol	Description	V_{CCIO} (V)	Typical	Unit
dR/dT	OCT variation with temperature without recalibration	3.0	0.189	%/°C
		2.5	0.208	
		1.8	0.266	
		1.5	0.273	
		1.2	0.317	

Note to Table 13:

(1) Valid for a V_{CCIO} range of ±5% and a temperature range of 0° to 85°C.

Pin Capacitance

Table 14 lists the Stratix V device family pin capacitance.

Table 14. Pin Capacitance for Stratix V Devices

Symbol	Description	Value	Unit
C_{IOTB}	Input capacitance on the top and bottom I/O pins	6	pF
C_{IOLR}	Input capacitance on the left and right I/O pins	6	pF
C_{OUTFB}	Input capacitance on dual-purpose clock output and feedback pins	6	pF

Hot Socketing

Table 15 lists the hot socketing specifications for Stratix V devices.

Table 15. Hot Socketing Specifications for Stratix V Devices

Symbol	Description	Maximum
$I_{IOPIN (DC)}$	DC current per I/O pin	300 μA
$I_{IOPIN (AC)}$	AC current per I/O pin	8 mA (1)
$I_{XCVR-TX (DC)}$	DC current per transceiver transmitter pin	100 mA
$I_{XCVR-RX (DC)}$	DC current per transceiver receiver pin	50 mA

Note to Table 15:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}|$ = C dv/dt, in which C is the I/O pin capacitance and dv/dt is the slew rate.

Table 21. Differential HSTL and HSUL I/O Standards for Stratix V Devices (Part 2 of 2)

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V_{CCIO} + 0.3	—	0.5* V_{CCIO}	—	0.4* V_{CCIO}	0.5* V_{CCIO}	0.6* V_{CCIO}	0.3	V_{CCIO} + 0.48
HSUL-12	1.14	1.2	1.3	0.26	0.26	0.5*V_{CCIO} – 0.12	0.5* V_{CCIO}	0.5*V_{CCIO} + 0.12	0.4* V_{CCIO}	0.5* V_{CCIO}	0.6* V_{CCIO}	0.44	0.44

Table 22. Differential I/O Standard Specifications for Stratix V Devices *(7)*

I/O Standard	V_{CCIO} (V) *(10)*			V_{ID} (mV) *(8)*			$V_{ICM(DC)}$ (V)			V_{OD} (V) *(6)*			V_{OCM} (V) *(6)*		
	Min	Typ	Max	Min	Condition	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
PCML	Transmitter, receiver, and input reference clock pins of the high-speed transceivers use the PCML I/O standard. For transmitter, receiver, and reference clock I/O pin specifications, refer to Table 23 on page 18.														
2.5 V LVDS *(1)*	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.05	$D_{MAX} \leq$ 700 Mbps	1.8	0.247	—	0.6	1.125	1.25	1.375
						—	1.05	$D_{MAX} >$ 700 Mbps	1.55	0.247	—	0.6	1.125	1.25	1.375
BLVDS *(5)*	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—	—
RSDS (HIO) *(2)*	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.3	—	1.4	0.1	0.2	0.6	0.5	1.2	1.4
Mini-LVDS (HIO) *(3)*	2.375	2.5	2.625	200	—	600	0.4	—	1.325	0.25	—	0.6	1	1.2	1.4
LVPECL *(4), (9)*	—	—	—	300	—	—	0.6	$D_{MAX} \leq$ 700 Mbps	1.8	—	—	—	—	—	—
	—	—	—	300	—	—	1	$D_{MAX} >$ 700 Mbps	1.6	—	—	—	—	—	—

Notes to Table 22:

(1) For optimized LVDS receiver performance, the receiver voltage input range must be between 1.0 V to 1.6 V for data rates above 700 Mbps, and 0 V to 1.85 V for data rates below 700 Mbps.

(2) For optimized RSDS receiver performance, the receiver voltage input range must be between 0.25 V to 1.45 V.

(3) For optimized Mini-LVDS receiver performance, the receiver voltage input range must be between 0.3 V to 1.425 V.

(4) For optimized LVPECL receiver performance, the receiver voltage input range must be between 0.85 V to 1.75 V for data rate above 700 Mbps and 0.45 V to 1.95 V for data rate below 700 Mbps.

(5) There are no fixed V_{ICM}, V_{OD}, and V_{OCM} specifications for BLVDS. They depend on the system topology.

(6) RL range: $90 \leq RL \leq 110\ \Omega$.

(7) The 1.4-V and 1.5-V PCML transceiver I/O standard specifications are described in “Transceiver Performance Specifications” on page 18.

(8) The minimum VID value is applicable over the entire common mode range, VCM.

(9) LVPECL is only supported on dedicated clock input pins.

(10) Differential inputs are powered by VCCPD which requires 2.5 V.

Power Consumption

Altera offers two ways to estimate power consumption for a design—the Excel-based Early Power Estimator and the Quartus® II PowerPlay Power Analyzer feature.

Switching Characteristics

This section provides performance characteristics of the Stratix V core and periphery blocks.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The title of these tables show the designation as "Preliminary."
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

Transceiver Performance Specifications

This section describes transceiver performance specifications.

Table 23 lists the Stratix V GX and GS transceiver specifications.

Table 23. Transceiver Specifications for Stratix V GX and GS Devices (1) (Part 1 of 7)

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Reference Clock											
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL									
	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS									
Input Reference Clock Frequency (CMU PLL) (8)	—	40	—	710	40	—	710	40	—	710	MHz
Input Reference Clock Frequency (ATX PLL) (8)	—	100	—	710	100	—	710	100	—	710	MHz
Rise time	Measure at ±60 mV of differential signal (26)	—	—	400	—	—	400	—	—	400	ps
Fall time	Measure at ±60 mV of differential signal (26)	—	—	400	—	—	400	—	—	400	
Duty cycle	—	45	—	55	45	—	55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express® (PCIe®)	30	—	33	30	—	33	30	—	33	kHz

Table 23. Transceiver Specifications for Stratix V GX and GS Devices *(1)* **(Part 4 of 7)**

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors *(21)*	85–Ω setting	—	85 ± 30%	—	—	85 ± 30%	—	—	85 ± 30%	—	Ω
	100–Ω setting	—	100 ± 30%	—	—	100 ± 30%	—	—	100 ± 30%	—	Ω
	120–Ω setting	—	120 ± 30%	—	—	120 ± 30%	—	—	120 ± 30%	—	Ω
	150-Ω setting	—	150 ± 30%	—	—	150 ± 30%	—	—	150 ± 30%	—	Ω
V_{ICM} (AC and DC coupled)	V_{CCR_GXB} = 0.85 V or 0.9 V full bandwidth	—	600	—	—	600	—	—	600	—	mV
	V_{CCR_GXB} = 0.85 V or 0.9 V half bandwidth	—	600	—	—	600	—	—	600	—	mV
	V_{CCR_GXB} = 1.0 V/1.05 V full bandwidth	—	700	—	—	700	—	—	700	—	mV
	V_{CCR_GXB} = 1.0 V half bandwidth	—	750	—	—	750	—	—	750	—	mV
t_{LTR} *(11)*	—	—	—	10	—	—	10	—	—	10	µs
t_{LTD} *(12)*	—	4	—	—	4	—	—	4	—	—	µs
t_{LTD_manual} *(13)*	—	4	—	—	4	—	—	4	—	—	µs
$t_{LTR\_LTD\_manual}$ *(14)*	—	15	—	—	15	—	—	15	—	—	µs
Run Length	—	—	—	200	—	—	200	—	—	200	UI
Programmable equalization (AC Gain) *(10)*	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)	—	—	16	—	—	16	—	—	16	dB

Table 26 shows the approximate maximum data rate using the 10G PCS.

Table 26. Stratix V 10G PCS Approximate Maximum Data Rate *(1)*

Mode *(2)*	**Transceiver Speed Grade**	**PMA Width**	**64**	**40**	**40**	**40**	**32**	**32**
		PCS Width	**64**	**66/67**	**50**	**40**	**64/66/67**	**32**
FIFO or Register	1	C1, C2, C2L, I2, I2L core speed grade	14.1	14.1	10.69	14.1	13.6	13.6
	2	C1, C2, C2L, I2, I2L core speed grade	12.5	12.5	10.69	12.5	12.5	12.5
		C3, I3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88
	3	C1, C2, C2L, I2, I2L core speed grade	8.5 Gbps					
		C3, I3, I3L core speed grade						
		C4, I4 core speed grade						
		I3YY core speed grade	10.3125 Gbps					

Notes to Table 26:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5) (1)

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors (7)	GT channels	—	100	—	—	100	—	Ω
Differential on-chip termination resistors for GX channels (19)	85-Ω setting	—	85 ± 30%	—	—	85 ± 30%	—	Ω
	100-Ω setting	—	100 ± 30%	—	—	100 ± 30%	—	Ω
	120-Ω setting	—	120 ± 30%	—	—	120 ± 30%	—	Ω
	150-Ω setting	—	150 ± 30%	—	—	150 ± 30%	—	Ω
V_{ICM} (AC coupled)	GT channels	—	650	—	—	650	—	mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 0.85 V or 0.9 V	—	600	—	—	600	—	mV
	VCCR_GXB = 1.0 V full bandwidth	—	700	—	—	700	—	mV
	VCCR_GXB = 1.0 V half bandwidth	—	750	—	—	750	—	mV
t_{LTR} (9)	—	—	—	10	—	—	10	µs
t_{LTD} (10)	—	4	—	—	4	—	—	µs
t_{LTD_manual} (11)	—	4	—	—	4	—	—	µs
$t_{LTR\_LTD\_manual}$ (12)	—	15	—	—	15	—	—	µs
Run Length	GT channels	—	—	72	—	—	72	CID
	GX channels	(8)						
CDR PPM	GT channels	—	—	1000	—	—	1000	± PPM
	GX channels	(8)						
Programmable equalization (AC Gain) (5)	GT channels	—	—	14	—	—	14	dB
	GX channels	(8)						
Programmable DC gain (6)	GT channels	—	—	7.5	—	—	7.5	dB
	GX channels	(8)						
Differential on-chip termination resistors (7)	GT channels	—	100	—	—	100	—	Ω
Transmitter								
Supported I/O Standards	—	1.4-V and 1.5-V PCML						
Data rate (Standard PCS)	GX channels	600	—	8500	600	—	8500	Mbps
Data rate (10G PCS)	GX channels	600	—	12,500	600	—	12,500	Mbps

Table 29 shows the V_{OD} settings for the GT channel.

Table 29. Typical V_{OD} Setting for GT Channel, TX Termination = 100 Ω

Symbol	V_{OD} Setting	V_{OD} Value (mV)
V_{OD} differential peak to peak typical *(1)*	0	0
	1	200
	2	400
	3	600
	4	800
	5	1000

Note:

(1) Refer to Figure 4.

Figure 4 shows the differential transmitter output waveform.

Figure 4. Differential Transmitter/Receiver Output/Input Waveform

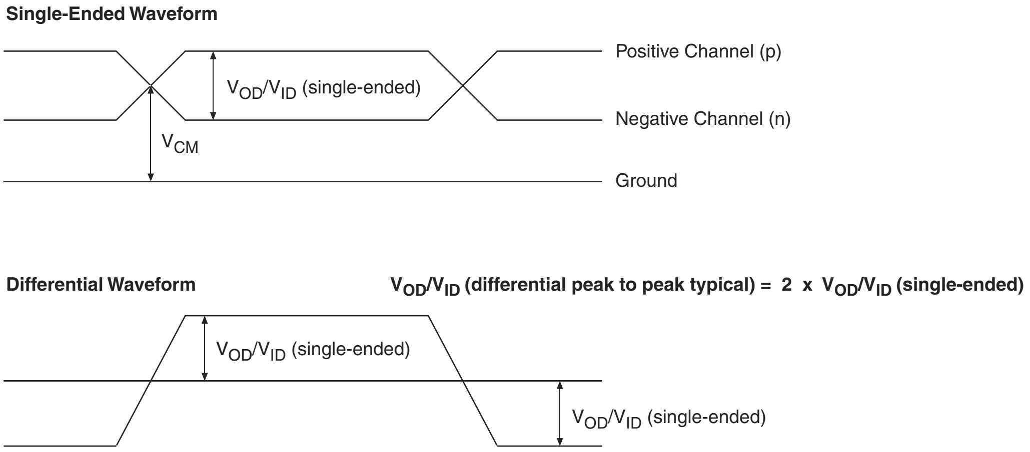


Figure 5 shows the Stratix V AC gain curves for GT channels.

Figure 5. AC Gain Curves for GT Channels

PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85°C) and the industrial junction temperature range (–40° to 100°C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
f_{IN}	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5	—	800 (1)	MHz
	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5	—	800 (1)	MHz
	Input clock frequency (C4, I4 speed grades)	5	—	650 (1)	MHz
f_{INPFD}	Input frequency to the PFD	5	—	325	MHz
f_{FINPFD}	Fractional Input clock frequency to the PFD	50	—	160	MHz
f_{VCO} (9)	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	—	1600	MHz
	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600	—	1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
$t_{EINDUTY}$	Input clock or external feedback clock input duty cycle	40	—	60	%
f_{OUT}	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	—	—	717 (2)	MHz
	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)	—	—	650 (2)	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)	—	—	580 (2)	MHz
f_{OUT_EXT}	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)	—	—	800 (2)	MHz
	Output frequency for an external clock output (C3, I3, I3L speed grades)	—	—	667 (2)	MHz
	Output frequency for an external clock output (C4, I4 speed grades)	—	—	553 (2)	MHz
$t_{OUTDUTY}$	Duty cycle for a dedicated external clock output (when set to **50%**)	45	50	55	%
t_{FCOMP}	External feedback clock compensation time	—	—	10	ns
$f_{DYCONFIGCLK}$	Dynamic Configuration Clock used for `mgmt_clk` and `scanclk`	—	—	100	MHz
t_{LOCK}	Time required to lock from the end-of-device configuration or deassertion of `areset`	—	—	1	ms
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	—	—	1	ms
f_{CLBW}	PLL closed-loop low bandwidth	—	0.3	—	MHz
	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth (7)	—	4	—	MHz
t_{PLL_PSERR}	Accuracy of PLL phase shift	—	—	±50	ps
t_{ARESET}	Minimum pulse width on the `areset` signal	10	—	—	ns

Table 33. Memory Block Performance Specifications for Stratix V Devices (1), (2) (Part 2 of 2)

Memory	Mode	Resources Used		Performance							Unit
		ALUTs	Memory	C1	C2, C2L	C3	C4	I2, I2L	I3, I3L, I3YY	I4	
M20K Block	Single-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port with the read-during-write option set to **Old Data**, all supported widths	0	1	525	525	455	400	525	455	400	MHz
	Simple dual-port with ECC enabled, 512 × 32	0	1	450	450	400	350	450	400	350	MHz
	Simple dual-port with ECC and optional pipeline registers enabled, 512 × 32	0	1	600	600	500	450	600	500	450	MHz
	True dual port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	ROM, all supported widths	0	1	700	700	650	550	700	500	450	MHz

Notes to Table 33:

(1) To achieve the maximum memory block performance, use a memory block clock that comes through global clock routing from an on-chip PLL set to **50%** output duty cycle. Use the Quartus II software to report timing for this and other memory block clocking schemes.

(2) When you use the error detection cyclical redundancy check (CRC) feature, there is no degradation in F_{MAX}.

(3) The F_{MAX} specification is only achievable with Fitter options, **MLAB Implementation In 16-Bit Deep Mode** enabled.

Temperature Sensing Diode Specifications

Table 34 lists the internal TSD specification.

Table 34. Internal Temperature Sensing Diode Specification

Temperature Range	Accuracy	Offset Calibrated Option	Sampling Rate	Conversion Time	Resolution	Minimum Resolution with no Missing Codes
–40°C to 100°C	±8°C	No	1 MHz, 500 KHz	< 100 ms	8 bits	8 bits

Table 35 lists the specifications for the Stratix V external temperature sensing diode.

Table 35. External Temperature Sensing Diode Specifications for Stratix V Devices

Description	Min	Typ	Max	Unit
I_{bias}, diode source current	8	—	200	μA
V_{bias}, voltage across diode	0.3	—	0.9	V
Series resistance	—	—	< 1	Ω
Diode ideality factor	1.006	1.008	1.010	—

Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 2 of 4)

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Transmitter														
True Differential I/O Standards - f_{HSDR} (data rate)	SERDES factor J = 3 to 10 (9), (11), (12), (13), (14), (15), (16)	(6)	—	1600	(6)	—	1434	(6)	—	1250	(6)	—	1050	Mbps
	SERDES factor J ≥ 4 LVDS TX with DPA (12), (14), (15), (16)	(6)	—	1600	(6)	—	1600	(6)	—	1600	(6)	—	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	(6)	—	(7)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f_{HSDR} (data rate) (10)	SERDES factor J = 4 to 10 (17)	(6)	—	1100	(6)	—	1100	(6)	—	840	(6)	—	840	Mbps
$t_{x\ Jitter}$ - True Differential I/O Standards	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	—	—	160	—	—	160	—	—	160	—	—	160	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.1	—	—	0.1	—	—	0.1	—	—	0.1	UI
$t_{x\ Jitter}$ - Emulated Differential I/O Standards with Three External Output Resistor Network	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	—	—	300	—	—	300	—	—	300	—	—	325	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.2	—	—	0.2	—	—	0.2	—	—	0.25	UI

Table 36. High-Speed I/O Specifications for Stratix V Devices *(1), (2)* **(Part 4 of 4)**

Symbol	**Conditions**	**C1**			**C2, C2L, I2, I2L**			**C3, I3, I3L, I3YY**			**C4,I4**			**Unit**
		Min	**Typ**	**Max**	**Min**	**Typ**	**Max**	**Min**	**Typ**	**Max**	**Min**	**Typ**	**Max**	
f_{HSDR} (data rate)	SERDES factor J = 3 to 10	*(6)*	—	*(8)*	*(6)*	—	*(8)*	*(6)*	—	*(8)*	*(6)*	—	*(8)*	Mbps
	SERDES factor J = 2, uses DDR Registers	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	Mbps
	SERDES factor J = 1, uses SDR Register	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	*(6)*	—	*(7)*	Mbps
DPA Mode														
DPA run length	—	—	—	10000	—	—	10000	—	—	10000	—	—	10000	UI
Soft CDR mode														
Soft-CDR PPM tolerance	—	—	—	300	—	—	300	—	—	300	—	—	300	± PPM
Non DPA Mode														
Sampling Window	—	—	—	300	—	—	300	—	—	300	—	—	300	ps

Notes to Table 36:

(1) When J = 3 to 10, use the serializer/deserializer (SERDES) block.

(2) When J = 1 or 2, bypass the SERDES block.

(3) This only applies to DPA and soft-CDR modes.

(4) Clock Boost Factor (W) is the ratio between the input data rate to the input clock rate.

(5) This is achieved by using the **LVDS** clock network.

(6) The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.

(7) The maximum ideal frequency is the SERDES factor (J) x the PLL maximum output frequency (fOUT) provided you can close the design timing and the signal integrity simulation is clean.

(8) You can estimate the achievable maximum data rate for non-DPA mode by performing link timing closure analysis. You must consider the board skew margin, transmitter delay margin, and receiver sampling margin to determine the maximum data rate supported.

(9) If the receiver with DPA enabled and transmitter are using shared PLLs, the minimum data rate is 150 Mbps.

(10) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine leftover timing margin.

(11) The F_{MAX} specification is based on the fast clock used for serial data. The interface F_{MAX} is also dependent on the parallel clock domain which is design-dependent and requires timing analysis.

(12) Stratix V RX LVDS will need DPA. For Stratix V TX LVDS, the receiver side component must have DPA.

(13) Stratix V LVDS serialization and de-serialization factor needs to be x4 and above.

(14) Requires package skew compensation with PCB trace length.

(15) Do not mix single-ended I/O buffer within LVDS I/O bank.

(16) Chip-to-chip communication only with a maximum load of 5 pF.

(17) When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.

Figure 7 shows the dynamic phase alignment (DPA) lock time specifications with the DPA PLL calibration option enabled.

Figure 7. DPA Lock Time Specification with DPA PLL Calibration Enabled

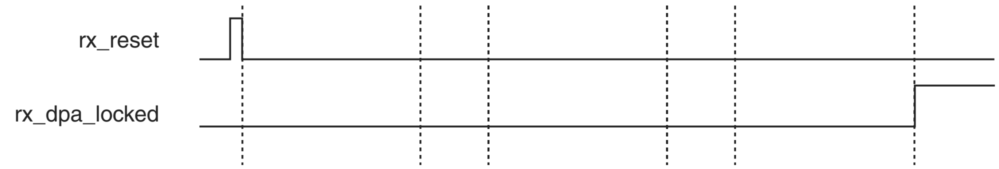


Table 37 lists the DPA lock time specifications for Stratix V devices.

Table 37. DPA Lock Time Specifications for Stratix V GX Devices Only *(1), (2), (3)*

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions *(4)*	Maximum
SPI-4	00000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

Notes to Table 37:

(1) The DPA lock time is for one channel.

(2) One data transition is defined as a 0-to-1 or 1-to-0 transition.

(3) The DPA lock time stated in this table applies to both commercial and industrial grade.

(4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 8 shows the **LVDS** soft-clock data recovery (CDR)/DPA sinusoidal jitter tolerance specification for a data rate ≥ 1.25 Gbps. Table 38 lists the **LVDS** soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate ≥ 1.25 Gbps.

Figure 8. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate ≥ 1.25 Gbps

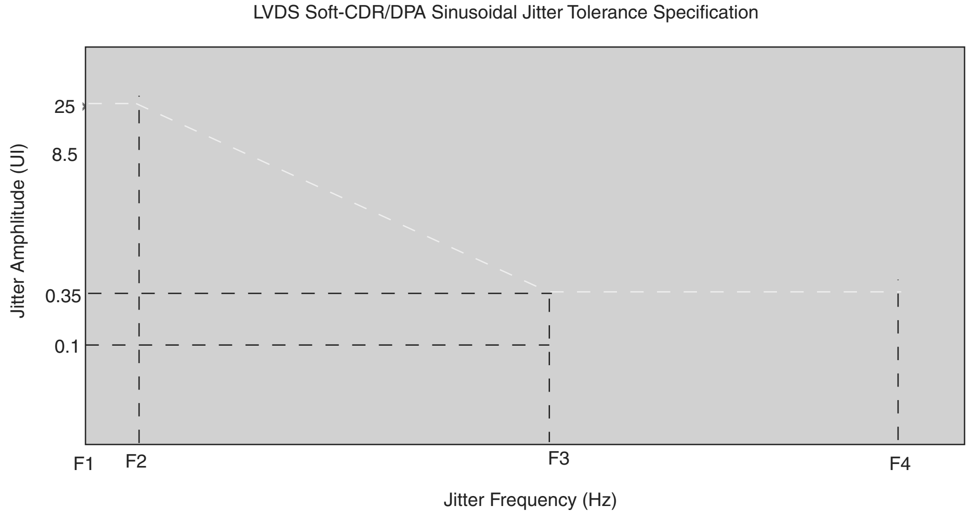
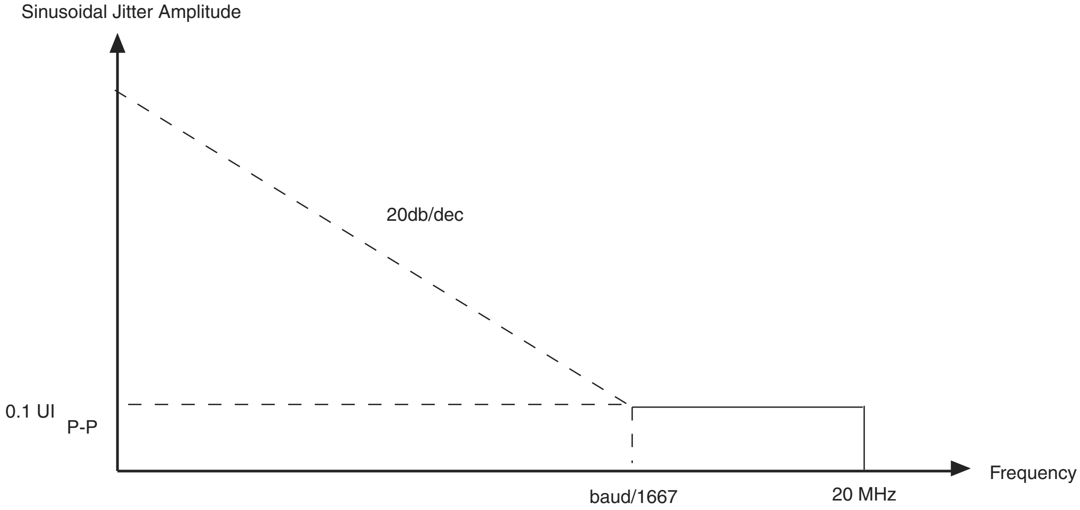


Table 38. LVDS Soft-CDR/DPA Sinusoidal Jitter Mask Values for a Data Rate ≥ 1.25 Gbps

Jitter Frequency (Hz)		Sinusoidal Jitter (UI)
F1	10,000	25.000
F2	17,565	25.000
F3	1,493,000	0.350
F4	50,000,000	0.350

Figure 9 shows the **LVDS** soft-CDR/DPA sinusoidal jitter tolerance specification for a data rate < 1.25 Gbps.

Figure 9. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for a Data Rate < 1.25 Gbps



DLL Range, DQS Logic Block, and Memory Output Clock Jitter Specifications

Table 39 lists the DLL range specification for Stratix V devices. The DLL is always in 8-tap mode in Stratix V devices.

Table 39. DLL Range Specifications for Stratix V Devices (1)

C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,I4	Unit
300-933	300-933	300-890	300-890	MHz

Note to Table 39:

(1) Stratix V devices support memory interface frequencies lower than 300 MHz, although the reference clock that feeds the DLL must be at least 300 MHz. To support interfaces below 300 MHz, multiply the reference clock feeding the DLL to ensure the frequency is within the supported range of the DLL.

Table 40 lists the DQS phase offset delay per stage for Stratix V devices.

Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices (1), (2) (Part 1 of 2)

Speed Grade	Min	Max	Unit
C1	8	14	ps
C2, C2L, I2, I2L	8	14	ps
C3,I3, I3L, I3YY	8	15	ps

Duty Cycle Distortion (DCD) Specifications

Table 44 lists the worst-case DCD for Stratix V devices.

Table 44. Worst-Case DCD on Stratix V I/O Pins (1)

Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,I4		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	45	55	45	55	%

Note to Table 44:

(1) The DCD numbers do not cover the core clock network.

Configuration Specification

POR Delay Specification

Power-on reset (POR) delay is defined as the delay between the time when all the power supplies monitored by the POR circuitry reach the minimum recommended operating voltage to the time when the `nSTATUS` is released high and your device is ready to begin configuration.

For more information about the POR delay, refer to the *Hot Socketing and Power-On Reset in Stratix V Devices* chapter.

Table 45 lists the fast and standard POR delay specification.

Table 45. Fast and Standard POR Delay Specification (1)

POR Delay	Minimum	Maximum
Fast	4 ms	12 ms
Standard	100 ms	300 ms

Note to Table 45:

(1) You can select the POR delay based on the `MSEL` settings as described in the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

JTAG Configuration Specifications

Table 46 lists the JTAG timing parameters and values for Stratix V devices.

Table 46. JTAG Timing Parameters and Values for Stratix V Devices

Symbol	Description	Min	Max	Unit
t_{JCP}	TCK clock period (2)	30	—	ns
t_{JCP}	TCK clock period (2)	167	—	ns
t_{JCH}	TCK clock high time (2)	14	—	ns
t_{JCL}	TCK clock low time (2)	14	—	ns
$t_{JPSU\ (TDI)}$	TDI JTAG port setup time	2	—	ns
$t_{JPSU\ (TMS)}$	TMS JTAG port setup time	3	—	ns

Table 48. Minimum Configuration Time Estimation for Stratix V Devices

Variant	Member Code	Active Serial (1)			Fast Passive Parallel (2)		
		Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)
GS	D3	4	100	0.344	32	100	0.043
	D4	4	100	0.534	32	100	0.067
		4	100	0.344	32	100	0.043
	D5	4	100	0.534	32	100	0.067
	D6	4	100	0.741	32	100	0.093
	D8	4	100	0.741	32	100	0.093
E	E9	4	100	0.857	32	100	0.107
	EB	4	100	0.857	32	100	0.107

Notes to Table 48:

(1) DCLK frequency of 100 MHz using external CLKUSR.

(2) Max FPGA FPP bandwidth may exceed bandwidth available from some external storage or control logic.

Fast Passive Parallel Configuration Timing

This section describes the fast passive parallel (FPP) configuration timing parameters for Stratix V devices.

DCLK-to-DATA[] Ratio for FPP Configuration

FPP configuration requires a different `DCLK`-to-`DATA[]` ratio when you enable the design security, decompression, or both features. Table 49 lists the `DCLK`-to-`DATA[]` ratio for each combination.

Table 49. DCLK-to-DATA[] Ratio (1) (Part 1 of 2)

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
FPP ×8	Disabled	Disabled	1
	Disabled	Enabled	1
	Enabled	Disabled	2
	Enabled	Enabled	2
FPP ×16	Disabled	Disabled	1
	Disabled	Enabled	2
	Enabled	Disabled	4
	Enabled	Enabled	4

Table 54 lists the PS configuration timing parameters for Stratix V devices.

Table 54. PS Timing Parameters for Stratix V Devices

Symbol	Parameter	Minimum	Maximum	Units
t_{CF2CD}	`nCONFIG` low to `CONF_DONE` low	—	600	ns
t_{CF2ST0}	`nCONFIG` low to `nSTATUS` low	—	600	ns
t_{CFG}	`nCONFIG` low pulse width	2	—	µs
t_{STATUS}	`nSTATUS` low pulse width	268	1,506 *(1)*	µs
t_{CF2ST1}	`nCONFIG` high to `nSTATUS` high	—	1,506 *(2)*	µs
t_{CF2CK} *(5)*	`nCONFIG` high to first rising edge on `DCLK`	1,506	—	µs
t_{ST2CK} *(5)*	`nSTATUS` high to first rising edge of `DCLK`	2	—	µs
t_{DSU}	`DATA[]` setup time before rising edge on `DCLK`	5.5	—	ns
t_{DH}	`DATA[]` hold time after rising edge on `DCLK`	0	—	ns
t_{CH}	`DCLK` high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	`DCLK` low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	`DCLK` period	$1/f_{MAX}$	—	s
f_{MAX}	`DCLK` frequency	—	125	MHz
t_{CD2UM}	`CONF_DONE` high to user mode *(3)*	175	437	µs
t_{CD2CU}	`CONF_DONE` high to `CLKUSR` enabled	4 × maximum `DCLK` period	—	—
t_{CD2UMC}	`CONF_DONE` high to user mode with `CLKUSR` option on	t_{CD2CU} + (8576 × `CLKUSR` period) *(4)*	—	—

Notes to Table 54:

(1) This value is applicable if you do not delay configuration by extending the `nCONFIG` or `nSTATUS` low pulse width.

(2) This value is applicable if you do not delay configuration by externally holding the `nSTATUS` low.

(3) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

(4) To enable the `CLKUSR` pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the "Initialization" section.

(5) If `nSTATUS` is monitored, follow the t_{ST2CK} specification. If `nSTATUS` is not monitored, follow the t_{CF2CK} specification.

Initialization

Table 55 lists the initialization clock source option, the applicable configuration schemes, and the maximum frequency.

Table 55. Initialization Clock Source Option and the Maximum Frequency

Initialization Clock Source	Configuration Schemes	Maximum Frequency	Minimum Number of Clock Cycles *(1)*
Internal Oscillator	AS, PS, FPP	12.5 MHz	8576
`CLKUSR`	AS, PS, FPP *(2)*	125 MHz	
`DCLK`	PS, FPP	125 MHz	

Notes to Table 55:

(1) The minimum number of clock cycles required for device initialization.

(2) To enable `CLKUSR` as the initialization clock source, turn on the **Enable user-supplied start-up clock (`CLKUSR`)** option in the Quartus II software from the **General** panel of the **Device and Pin Options** dialog box.

Remote System Upgrades

Table 56 lists the timing parameter specifications for the remote system upgrade circuitry.

Table 56. Remote System Upgrade Circuitry Timing Specifications

Parameter	Minimum	Maximum	Unit
$t_{RU\_nCONFIG}$ *(1)*	250	—	ns
$t_{RU\_nRSTIMER}$ *(2)*	250	—	ns

Notes to Table 56:

(1) This is equivalent to strobing the reconfiguration input of the ALTREMOTE_UPDATE megafunction high for the minimum timing specification. For more information, refer to the Remote System Upgrade State Machine section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

(2) This is equivalent to strobing the reset_timer input of the ALTREMOTE_UPDATE megafunction high for the minimum timing specification. For more information, refer to the User Watchdog Timer section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

User Watchdog Internal Circuitry Timing Specification

Table 57 lists the operating range of the 12.5-MHz internal oscillator.

Table 57. 12.5-MHz Internal Oscillator Specifications

Minimum	Typical	Maximum	Units
5.3	7.9	12.5	MHz

I/O Timing

Altera offers two ways to determine I/O timing—the Excel-based I/O Timing and the Quartus II Timing Analyzer.

Excel-based I/O timing provides pin timing performance for each device density and speed grade. The data is typically used prior to designing the FPGA to get an estimate of the timing budget as part of the link timing analysis. The Quartus II Timing Analyzer provides a more accurate and precise I/O timing data based on the specifics of the design after you complete place-and-route.

You can download the Excel-based I/O Timing spreadsheet from the Stratix V Devices Documentation web page.

Programmable IOE Delay

Table 58 lists the Stratix V IOE programmable delay settings.

Table 58. IOE Programmable Delay for Stratix V Devices (Part 1 of 2)

Parameter *(1)*	Available Settings	Min Offset *(2)*	Fast Model		Slow Model							
			Industrial	Commercial	C1	C2	C3	C4	I2	I3, I3YY	I4	Unit
D1	64	0	0.464	0.493	0.838	0.838	0.924	1.011	0.844	0.921	1.006	ns
D2	32	0	0.230	0.244	0.415	0.415	0.459	0.503	0.417	0.456	0.500	ns